DECEMBER 1972-REVISED MARCH 1988

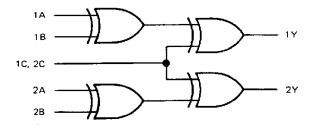
- Fully Compatible with Most TTL and TTL MSI Circuits
- Fully Schottky Clamping Reduces Delay Times . . . 8 ns Typical
- Can Operate as Exclusive-OR Gate (C Input Low) or as Exclusive-NOR Gate (C Input High)

FUNCTION TABLE

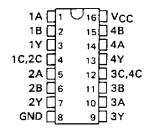
	INPUTS	OUTPUT	
Α	В	С	Y
L	L	L	L
L	н	L	н
H	L	L	н
Н	Н	L	L
L	L	н	н
L	н	н	L
Н	L	н	L
Ιн	н	н	н

H = high level, L = low level

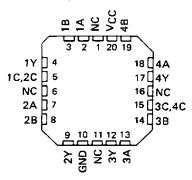
logic diagram (one half)



SN54S135 . . . J OR W PACKAGE SN74S135 . . . D OR N PACKAGE (TOP VIEW)



SN54S135 . . . FK PACKAGE (TOP VIEW)

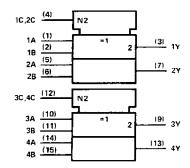


NC - No internal connection

positive logic

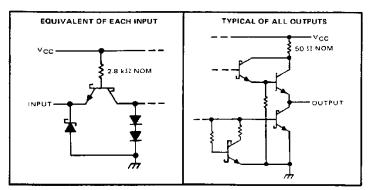
$$Y = A \oplus B \oplus C = A\overline{B}\overline{C} + \overline{A}B\overline{C} - \overline{A}\overline{B}C + ABC$$

logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers are for D, J, N, and W packages.

schematics of inputs and outputs



Resistor values shown are nominal.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54S135, SN74S135 QUADRUPLE EXCLUSIVE OR/NOR GATES

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	-	-												7 V
Input voltage	-										_		. !	5,5 V
Operating free-air temperature range: SN54S13	5											-55°	C to 1	25°C
SN74S13	5											0	°C to	70°C
Storage temperature range												-65°	C to 1	50°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	S	N54S1	35	S			
	MIN	NOM	MAX	MIN	NOM	MAX	TIMU
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-1			-1	mΑ
Low-level output current, IOL			20			20	mΑ
Operating free-air temperature, TA	-65		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	1	MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage			2			V
VIL	Low-level input voltage					0.8	V
VIK	Input clamp voltage	V _{CC} = MIN, I _I = -18 mA		_		-1.2	$\overline{}$
VOH	High-level output voltage	VCC = MIN, VIH = 2 V, SN	54 S ′	2.5	3.4	_	·
VOH	Trigitalever output voltage	V ₁ L = 0.8 V, I _{OH} = -1 mA SN	745'	2.7	3.4		V
VOL	Low-level output voltage	V _{CC} = MIN, V _{IH} = 2 V,			**		
*UL	activate output vortage	V _{IL} = 0.8 V, I _{OL} = 20 mA				0.5	\
ų	Input current at maximum input voltage	V _{CC} = MAX, V _I = 5.5 V				1	mΑ
Ιн	High-level input current	V _{CC} = MAX, V _I = 2.7 V				50	μА
ΙΙL	Low-level input current	V _{CC} = MAX, V ₁ = 0.5 V				-2	mΑ
los	Short-circuit output current §	V _{CC} = MAX		40		-100	mΑ
¹ CC	Supply current	VCC = MAX, See Note 2			65	99	mA

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. \ddagger All typical values are at \lor CC = \$ V, TA = 25° C. \$ Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	FROM (INPUT)	TEST CON	IDITIONS	MIN	TYP	мах	דומט		
t P LH	A or B	B A - I O - I			8.5	13			
†PHŁ		B or A = L, C = L	C _L = 15 pF, R _L = 280 Ω, See Note 3		11	15	ns		
^t PLH	A or B	B or A = H, C = L			 		8	12	_
^t PHL	7	BUIA-H,C-L				9	13.5	ns	
tPLH	A or B	Band - L C - H			10	15			
^t PHL	1 A or B	B or A = L, C = H			6.5	10	ns		
tPLH	A or B	2 - 1 2 11		 	8.5	12	— ns		
^t PHL	A OI B	B or A = H, C = H			7	13			
t P LH	C A = B C A ≠ B		8	12	 				
^t PHL		A = B			9.5	14.5	ns		
^t PLH		A + B	1		7.5	11.5			
^T PHL		(A # B			8	12	ns		

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



NOTE 2: $I_{\mbox{\footnotesize{CC}}}$ is measured with the inputs grounded and the outputs open.

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